

Laser Interferometry and Applications, Publications list (1994 to present):

2008

ISI:

P.C. Logofatu, A. Sima, B. Ionita, I. Iordache, D. Apostol, "The characterization of gratings using the optical scatterometer", J. Optoelectron. Adv. M., (2008) (in press)

F. Garoi, D. Apostol, P. Schiopu, P.C. Logofatu and V. Damian, "Traceable vibration amplitude measurement with a laser interferometer" J. Optoelectron. Adv. M., (2008) (in press)

P.C. Logofatu, I. Ardelean, D. Apostol, I. Iordache, M. Bojan, C. Moiescu, B. Ionita, "Determination of the magnetic moment and geometrical dimensions of the magnetotactic bacteria using an optical scattering method", Journal of Applied Physics 103(9) 094911 (2008)

P.C. Logofatu, D. Apostol, "Fully statistical approach for regression analysis," Measurement (2008) (in press)

D. Apostol, P.C. Logofatu, S. Florea, V. Damian, I. Iordache, M. Bojan, "Accurate calibration of grating pitch", J. Optoelectron. Adv. M., 10(2), 352-355 (2008)

A. Sima, P.C. Logofatu, B. Ionita, D. Apostol, "Real-time DHI for translation and deformation measurements using phase modulation SLM", J. Optoelectron. Adv. M., (2008) (in press)

A. Sima, B. Ionita, P. C. Logofatu, D. Apostol, I Ardelean, C. Moiescu, "Real-time DHI for gradient study in dynamic phase objects using Phase Only SLM", Laser Phys., 2008 (in press)

M. Rosu, B. Ionita, D. Apostol, F. Garoi, P.C. Logofatu, "Histogram equalization and specification in interferometry", J. Optoelectron. Adv. M., (2008) (in press)

Bogdan Ionita, Petre Catalin Logofatu, Florin Garoi, Iuliana Iordache, Dan Apostol, "Precise interferometric length measurement using real-time fringe

fitting," Meas. Sci. Technol. 2008, (in press)

Ramona Enea, Ileana Apostol, V Damian, N Hurduc, Iuliana Iordache,
"Photo-sensible (thymine containing) azo-polysiloxanes:synthesis and light
induced effects", Journal of Physics: Conference Series 100 (2008) 012022
ON WEB

I.Sava, Ana-Maria Resmerita, Gabriela Lisa, V.Damian, N.Hurduc,
"Synthesis and photochromic behavior of new polyimides containing
azobenzene side groups", Polymer 49, 1475 -1482 (2008)

Non-ISI:

D. Apostol, V. Damian, P.C. Logofatu, "Nanometrology for microsystems:
interferometry," Romanian Reports in Physics, (2008) in press

Invited papers:

Petre Catalin Logofatu, Adrian Sima, Dan Apostol, "Diffraction experiments
with the spatial light modulator: the boundary between physical and digital
optics," ATOM-N 2008, in press SPIE

Proceedings:

P.C. Logofatu, D. Apostol, A. Dinescu, R. Muller, D. Cristea,
"OPTIMIZATION OF WIREGRID POLARIZERS FOR CO2 LASER," CAS
2008 International Semiconductor Conference, in press

F. Garoi, D. Apostol, P. Schiopu, P.C. Logofatu, V. Damian, "Nano-
metrology of macro-systems," ATOM-N 2008, in press

2007

Victor Nascov, Dan Apostol, Florin Garoi, "Statistical processing of
Newton's rings using discrete Fourier analysis" Opt. Eng. 46 (2): art. No.
028201 (Feb 2007)

A. K. Sharma, P. C. Logofatu, C. S. Mayberry, S. R. J. Brueck and N. E.
Islam, "Effects of dimensional nanoscaling on the optical and electrical
properties of crystalline Si thin films", Journal of Applied Physics,
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P. C. Logofatu, D. Apostol, "The Fourier transform in optics: from continuous to discrete or from analogous experiment to digital calculus", J. Optoelectron. Adv. M., 9(9), 2838-2846 (2007)

Petre C. Logofatu; Ileana Apostol; Marie-Claude Castex; Victor Damian; Iuliana Iordache; Mihaela Bojan; Dan Apostol, "Structure modeling for scatterometric characterization of photoinduced surface-relief gratings", Proc SPIE 6617, pp 661717-1,12, "Modeling aspects in optical metrology", H. Bosse B. ed (2007)

Mihaela Bojan, D. Apostol, V. Damian, P.C. Logofatu, F. Garoi, Iuliana Iordache, "Refractive Index Measurement Using Comparative Interferometry" in Advanced Topics in Optoelectronics, Microelectronics, and Nanotechnologies III, Proc SPIE 6635, 6635-0Q (Bucharest, Romania, 2006) 8 May 2007

Iuliana Iordache, Mihaela Bojan, D. Apostol, V. Damian, F. Garoi, P.C. Logofatu, Raluca Muller and B. Savu, "Optical encoder measurement technology" in Advanced Topics in Optoelectronics, Microelectronics, and Nanotechnologies III, Proc SPIE 6635, 6635-06 (Bucharest, Romania, 2006) 7 May 2007

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V. Damian, P.C. Logofatu, D. Apostol, L. Vekas, D. Bica, A. Damian, F. Garoi, I. Iordache, A. Sima, M. Bojan, "Magnetic liquid surface behavior to external stimulus" ROMOPTO 2006, Proc SPIE 6785 23, V.I. Vlad eds., (Bucharest, Romania, 2006) 1 August 2007

D. Apostol, A. Sima, P.C. Logofatu, F. Garoi, V. Nascov, V. Damian, Iuliana Iordache, "Fourier transform digital holography" ROMOPTO 2006: Eighth

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D. Apostol, A. Sima, P.C. Logofatu, F. Garoi, V. Damian, V. Nascov, Iuliana Iordache, "Static Fourier transform lamdbameter" ROMOPTO 2006: Eighth Conference on Optics, Valentin I. Vlad, Editors, Proc SPIE 6785 678521, 1 August 2007

P.C. Logofatu, D. Apostol, Marie-Claude Castex, Ileana Apostol, V. Damian, Iuliana Iordache, Raluca Muller, "Characterization of surface relief gratings of submicron period" ROMOPTO 2006 Eighth Conference on Optics, Valentin I. Vlad, Editors, Proc SPIE 6785, 67851V, Date: 1 August 2007

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P.C. Logofatu, D. Apostol, V. Damian, I. Iordache, M. Bojan, R. Muller, "Abeles method revisited", Appl. Opt. 45, 1120-1123 (2006)

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A. Dobroiu, R. Beigang, C. Otani, and K. Kawase - "Monolithic Fabry-Perot resonator for the measurement of optical constants in the terahertz range" - Applied Physics Letters 86, 231107 (2005)

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